## Application/Control No. Applicant(s)/Patent Under Reexamination CATABAY ET AL. Examiner Lisa A Kilday Applicant(s)/Patent Under Reexamination CATABAY ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-			
	В	US-			
	С	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	-	US-			
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	К	US-			
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## **FOREIGN PATENT DOCUMENTS**

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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
	C	Nalwa, Handbook of Low and High Dielectric Constant Materials and Their Applications, vol. 1, pg. 66, (1999)		
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.